

### **Features**

- 16-bit SAR ADC without Zero Latency
   Throughput Speed: 600 KSPS
- Unipolar, Differential Analog Input – -VREF to VREF
- External VREF
- 2.5 V to VDD
- High Linearity
- INL: ±1 LSB typical
- DNL: ±0.5 LSB typical
- THD: -91 dB at fin=1kHz, VREF=5V
- High Dynamic Range and Noise Performance
  - SNR
  - Dynamic Range
- Serial Interface:
  - SPI Compatible
- Daisy-chain Supported
- Package: MSOP10
- Wide Operating Temperature Range:
  - -40°C to +125°C
- Package: MSOP10

### **Applications**

- Data Acquisitions
- Instruments
- Industry Measurement and Control
- Medical Equipment
- Automatic Test Equipment

### Description

The TPC5160 is a 16-bit analog-to-digital converter (ADC). The device supports unipolar, differential input, and input range, which is -VREF ~VREF with a common-mode voltage of VREF/2.

The device operates with a 2.5 V to VDD external reference.

The device offers an SPI-compatible interface and supports daisy-chain operation for multiple devices application.

The device also offers an optional busy indicator bit, which can be used to synchronize with the host.

## **Typical Application Circuit**





## Product Family Table

Order Number	Resolution	Input range	Throughput speed	Package
TPC5160-VS2R	TPC5160-VS2R 16		600K SPS	MSOP10



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# **Revision History**

Date	Revision	Notes
2022-05-23	Rev.Pre.0	Pre-Release Version



## **Pin Configuration and Functions**



#### **Pin Functions**

Р	in	1/0	Description
No.	Name	I/O	Description
1	REF	I	Reference voltage.
2	VDD	0	Power supply.
3	IN+	0	Positive analog Input.
4	IN-	Ι	Negative analog Input.
5	GND	-	Power Ground.
6	CNV		<ul> <li>Conversion input. It initiates the conversions of the device, and selects the interface mode together with SDI.</li> <li>Chain mode: SDI is low during CNV rising edge</li> <li>CS mode: SDI is high during CNV rising edge.</li> </ul>
7	SDO		Serial Data output.
8	SCK		Serial Data clock.
9	SDI		Serial Data input. It selects the serial mode together with CNV.
10	VIO		Digital interface power.



### **Specifications**

#### **Absolute Maximum Ratings**

	Parameter	Min	Мах	Unit
	IN+, IN- to GND	-0.3	VDD + 0.3	V
Analog Voltage	VREF to GND	-0.3	VDD + 0.3	V
	Digital Inputs to GND	-0.3	VIO + 0.3	V
Digital Voltage	Digital Outputs to GND	-0.3	VIO + 0.3	V
Cummby ) (alta na	VDD to GND	-0.3	6	V
Supply Voltage	VIO to GND	-0.3	VDD+0.3	V
TJ	Maximum Junction Temperature	-40	150	°C
T <sub>A</sub>	Operating Temperature Range	-40	125	°C
T <sub>STG</sub>	Storage Temperature Range	-65	150	°C
TL	Lead Temperature (Soldering 10 sec)		260	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

#### **ESD, Electrostatic Discharge Protection**

Symbol	Parameter	Condition	Minimum Level	Unit
HBM	Human Body Model ESD	ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	3000	V
CDM	Charged Device Model ESD	ANSI/ESDA/JEDEC JS-002 <sup>(2)</sup>	2000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

#### **Recommended Operating Conditions**

Parameter	Min	Тур	Мах	Unit
VDD	4.5	5	5.5	V
REF	2.5	5	VDD	V
VIO	1.71	3.3	VDD	V

#### **Thermal Information**

Package Type	θ <sub>JA</sub>	θ」c	Unit
MSOP10			°C/W



#### **Electrical Characteristics**

All test conditions: VDD = 5 V, VIO = 1.71 V to 5 V, TA =  $-40^{\circ}$ C to  $+125^{\circ}$ C, unless otherwise noted.

Parameter	Test Co	ndition	Min	Тур	Max	Unit
AC Accuracy						
0115	6 4111	REF=5 V	87	92		dB
SNR	fin=1 kHz	REF=3 V	85.5	90		dB
	6 4 http://	REF=5 V		89		dB
SINAD	fin=1 kHz	REF=3 V		89		dB
	6 4 1 1 1	REF=5 V		92		dB
Dynamic Range	fin=1 kHz	REF=3 V		90		dB
THD	fin=1 kHz	REF=5 V		-91		dB
SFDR	fin=1 kHz	REF=5 V		-104		dB
IMD		fin1=255 kHz, fin2=285 kHz, Ain1&Ain2=−7 dBFS		NA		dB
Resolution	NO missing code		16			Bits
DC Accuracy						
DNL	REF=5 V		-1	±0.5	1	
DNL	REF=3 V			±0.8		LSB
INL	REF=5 V		-3	±1	3	LSB
	REF=3 V			±1.5		LOD
Transition Noise	REF=5 V			0.6		LSB
Transition Noise	REF=3 V			1		LOD
Gain Error				±5		LSB
Gain Error Drift	Y			±0.35		ppm/C
Zero Code Error			-1.3	±0.08	1.3	mV
Zero Code Error Drift				±0.35		ppm/C
Power Supply Sensitivity	AVDD +/-5%			±1.5		LSB
Analog Input						
Voltage Range	IN+ - IN-		-VREF		VREF	V
Common-Mode Input Range			VREF/2 – 0.1		VREF/2+0.1	
Operating Input	IN+		-0.1		VREF+0.1	V
Voltage	IN-		-0.1		VREF+0.1	V
Analog Input				75		dB



CMRR						
Leakage Current at 25°C				1		nA
Input Capacitance				34		pF
Throughput						
Conversion Rate			0		0.6	MHz
Acquisition Time			850	890		ns
Conversion Time				780	820	ns
Transient Response				890		ns
Reference						
REFERENCE Voltage Range			2.5		vcc	V
REFERENCE Load Current	1 MSPS, REF=5 V			130		uA
Sampling Dynami	cs					
-3 dB BW				20		MHz
Aperture Delay				4		ns
Digital Input						
VIH			0.7*VDD			V
VIL					0.3*VDD	V
IIH	input current		-2		2	uA
IIL	input current		-2		2	uA
Digital Output						
Data Format			S	erial 16bit straight bina	ary	
Pipeline Delay	N.			sults available immed completed conversior	-	
VOH	Output Logic High Voltage	current source=500 uA	VDRIVE-0.2			V
VOL	Output Logic Low Voltage	current sink=500 uA			0.2	V
Power Supply						
VDD			4.5		5.5	V
VIO			1.8		VDD	V
Standby Current				3000		uA
VDD Current	operating	fs=1 kHz	2.4	3	3.6	mA
(lavcc)	operating	fs=600 kHz	3.2	4	4.8	mA

(1) 100% tested at  $T_A = 25^{\circ}C$ .



#### **Timing Requirements**

All test conditions: VDD = 5 V, VIO = 1.71 V to 5 V, TA =  $-40^{\circ}$ C to  $+125^{\circ}$ C, unless otherwise noted.

Parameter	Symbol	Min	Тур	Max	Unit
Conversion Time: CNV Rising Edge to Data Available	tCONV	500		710	ns
Acquisition Time	tacq	290			ns
Time Between Conversions	tcyc	1000			ns
CNV Pulse Width (CS Mode)	tсмvн	10			ns
SCK Period (CS Mode)	tscк				ns
VIO Above 4.5 V		10.5			ns
VIO Above 3 V		12			ns
VIO Above 2.7 V		13			ns
VIO Above 2.3 V		15			ns
SCK Period (Chain Mode)	tscк				ns
VIO Above 4.5 V		11.5			ns
VIO Above 3 V		13			ns
VIO Above 2.7 V		14			ns
VIO Above 2.3 V		16			ns
SCK Low Time	tscĸ∟	4.5			ns
SCK High Time	tscкн	4.5			ns
SCK Falling Edge to Data Remains Valid	thsdo	3			ns
SCK Falling Edge to Data Valid Delay	tosdo				
VIO Above 4.5 V				9.5	ns
VIO Above 3 V				11	ns
VIO Above 2.7 V				12	ns
VIO Above 2.3 V				14	ns
CNV or SDI Low to SDO D15 MSB Valid (CS Mode)	ten				
VIO Above 3 V				10	ns
VIO Above 2.3 V				15	ns
CNV or SDI High or Last SCK Falling Edge to SDO High Impedance (CS Mode)	tois			20	ns
SDI Valid Setup Time from CNV Rising Edge	<b>t</b> ssdicnv	5			ns



SDI Valid Hold Time from CNV Rising Edge (CS Mode)	thsdicnv	2		ns
SDI Valid Hold Time from CNV Rising Edge (Chain Mode)	<b>t</b> HSDICNV	0		ns
SCK Valid Setup Time from CNV Rising Edge (Chain Mode)	tssckcnv	5		ns
SCK Valid Hold Time from CNV Rising Edge (Chain Mode)	tнscкcnv	5	7	ns
SDI Valid Setup Time from SCK Falling Edge (Chain Mode)	<b>t</b> ssdisck	2	Y	ns
SDI Valid Hold Time from SCK Falling Edge (Chain Mode)	thsdisck	3		ns
SDI High to SDO High (Chain Mode with Busy Indicator)	tosdosdi		15	ns



### **Detailed Description**

#### Overview

The TPC5160 is a 16-bit successive approximation register (SAR) ADC. The device is capable to convert analog input into digital output without latency or pipeline delay, so it is ideal for multiple-channel applications.

When a conversion is initiated, the analog input is sampled on internal capacitor, and then converted based on charge redistribution with an internal clock. During conversion, the input is disconnected from the internal capacitor.

After conversion, the device reconnects the sampling capacitors to input pins, and enters the acquisition phase.

#### **Functional Block Diagram**

#### **Feature Description**

#### Analog Input

The following figure is the equivalent input sampling circuit. The sampling switch is represented by a resistance in series with the ideal switch. The electrostatic discharge (ESD) protection diodes from both



analog inputs are also shown in the Figure.

Figure 1. Equivalent Input Sampling Circuit

#### Reference

The device operates with an external reference voltage. During the conversion process, internal capacitors are switched onto the reference terminal, and a dynamic charge is required. The switching frequency is proportional to the internal conversion clock frequency. A reference driver circuit is required to support the dynamic charge so that the noise and linearity performance of the device is not degraded.

#### **ADC Transfer Function**

The device is a unipolar, differential input device, and the output is in twos complement format. The transfer equation is shown in the following table:

Description	Analog Input	Digital output Code (Hex)		
Full-scale range	2*VREF	-		
Least Significant Bit (LSB)	2*VREF/65536	-		
Positive full scale	VREF – 1 LSB	7FFF		
Midscale	0 V	0000		
Midscale – 1 LSB	0 – 1LSB	FFFF		
Negative full scale	-VREF	8000		
	Full-scale range Least Significant Bit (LSB) Positive full scale Midscale Midscale – 1 LSB	Full-scale range2*VREFLeast Significant Bit (LSB)2*VREF/65536Positive full scaleVREF – 1 LSBMidscale0 VMidscale – 1 LSB0 – 1LSB		



#### **Device Function Modes**

The device offers  $\overline{\text{CS}}$  mode and Daisy-chain mode for interfacing with the host.

The mode in which the device operates depends on the SDI level when the CNV rising edge occurs. The device operates in  $\overline{CS}$  mode if SDI is high at the CNV rising edge. If SDI is low at the CNV rising edge, or if SDI and CNV are connected, the device operates in daisy-chain mode.

In  $\overline{CS}$  mode, the device is compatible with SPI hosts. This interface can use a 3-wire or 4-wire interface. The 3-wire interface uses the CNV, SCK, and SDO signals, and minimizes the wiring connections, and is useful for isolation applications. The 4-wire interface using the SDI, CNV, SCK, and SDO signals, allows the user to sample the analog input independent of the serial interface timing, and is useful to control an individual device while having multiple similar devices on board.

In daisy-chain mode, multiple devices can be cascaded on a single data line similar to a shift register. This mode is useful to reduce component count and signal traces on the board.

In both modes, the device can either operate with or without a busy indicator, where the busy indicator is a bit preceding the output data bits that can be used to interrupt the digital host and trigger the data transfer.

#### $\overline{\text{CS}}$ Mode

The device operates in  $\overline{CS}$  mode if SDI is high at the CNV rising edge. There are four different interface options available in this mode: 3-wire  $\overline{CS}$  mode without a busy indicator, 3-wire  $\overline{CS}$  mode with a busy indicator, 4-wire  $\overline{CS}$  mode without a busy indicator, and 4-wire  $\overline{CS}$  mode with a busy indicator.

#### 3-wire $\overline{CS}$ Mode without Busy Indicator

This mode is useful when a single ADC is connected to an SPI-compatible digital host.

In this mode, SDI can be connected to VIO. A CNV rising edge samples the input signal, causes the device to enter a conversion phase, and SDO is forced to 3-state. Conversion is done with an internal clock and continues regardless of the state of CNV. So CNV can be pulled low then to select other devices on the board.

However, CNV must return and hold high before the conversion time elapses. A high level on CNV at the end of the conversion ensures the device does not generate a busy indicator.



Figure 2. Connection Diagram: 3-Wire CS Mode without Busy Indicator







On the CNV falling edge, SDO comes out of 3-state and the device outputs the MSB of the data at first, and then low data bits on subsequent SCK falling edges.

The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.

SDO goes to 3-state after the 16th SCK falling edge or when CNV goes high, whichever occurs first.

#### 3-wire $\overline{CS}$ Mode with a Busy Indicator

This mode is useful when a single ADC is connected to an SPI-compatible digital host and an interrupt-driven data transfer is required.

In this mode, SDI can be connected to VIO. A CNV rising edge samples the input signal, causes the device to enter a conversion phase, and SDO is forced to 3-state.

Conversion is done with an internal clock and continues regardless of the state of CNV. So CNV can be pulled low then to select other devices on the board.

A pull-up resistor on the SDO pin ensures that  $\overline{IRQ}$  pin of the digital host is held high when SDO is in 3-state. However, CNV must be pulled low before conversion time elapses. A low level of CNV at the end of conversion ensures the device generates a busy indicator.



Figure 4. Connection Diagram: 3-Wire  $\overline{\text{CS}}$  Mode with a Busy Indicator





Figure 5. Timing Diagram: 3-Wire  $\overline{CS}$  Mode with a Busy Indicator

When the conversion is complete, the device enters an acquisition state. SDO comes out of 3-state, and outputs a busy indicator bit (low level). This feature provides a high-to-low transition on the  $\overline{IRQ}$  pin of the digital host.

Then the data bits are clocked out on the subsequent SCLK falling edges, MSB first.

The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.

SDO goes to 3-state after the 17th SCK falling edge or when CNV goes high, whichever occurs first.

#### 4-wire $\overline{\text{CS}}$ Mode without Busy Indicator

This mode is useful when one or more ADCs are connected to an SPI-compatible digital host. Following is the connection diagram of the two ADCs.

In this mode, SDI is controlled by the digital host and functions as  $\overline{CS}$ .







Figure 7. Timing Diagram: Two ADCs with 4-Wire CS Mode without Busy Indicator



When SDI is high, a CNV rising edge samples the input signal, causes the device to enter a conversion phase, and forces SDO to 3-state.

In this mode, CNV must be held high from the start of the conversion until all data bits are read.

Conversion is done with the internal clock regardless of the state of SDI. So SDI (functioning as  $\overline{CS}$ ) can be pulled low to select other devices on the board.

However, SDI must return and hold high before the conversion time elapse. A high level on SDI at the end of the conversion ensures the device does not generate a busy indicator.

On the SDI falling edge, SDO comes out of 3-state and the device outputs the MSB of the data at first, and then low data bits on subsequent SCK falling edges.

The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.

SDO goes to 3-state after the 16th SCK falling edge or when SDI goes high, whichever occurs first. When multiple devices are connected on the same data bus, the SDI of the second device (functioning as  $\overline{CS}$  for the second device) can go low after the first device data are read, and the SDO of the first device is in 3-state.

Care must be taken so that CNV and SDO of the devices are not low together during the read cycle.

#### 4-wire $\overline{\text{CS}}$ Mode with a Busy Indicator

This mode is most useful when a single ADC is connected to a digital host and an interrupt-driven data transfer is desired.

In this mode, SDI is controlled by the digital host and functions as  $\overline{CS}$ .

A pull-up resistor on SDO pin ensures that  $\overline{IRQ}$  pin of the digital host is held high when SDO is in 3-state. When SDI is high, a CNV rising edge samples the input signal, causes the device to enter a conversion phase, and forces SDO to 3-state.

In this mode, CNV must be held high from the start of the conversion until all data bits are read.

Conversion is done with the internal clock regardless of the state of SDI. So, SDI (functioning as  $\overline{CS}$ ) can be pulled low to select other devices on the board.

However, CNV must be pulled low before conversion time elapses. A low level of CNV at the end of conversion ensures the device generates a busy indicator.



Figure 8. Connection Diagram: 4-Wire CS Mode with a Busy Indicator





Figure 9. Timing Diagram: 4-Wire  $\overline{CS}$  Mode with a Busy Indicator

When the conversion is complete, the device enters an acquisition state. SDO comes out of 3-state, and outputs a busy indicator bit (low level). This feature provides a high-to-low transition on the  $\overline{IRQ}$  pin of the digital host.

Then the data bits are clocked out on the subsequent SCLK falling edges, MSB first.

The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.

SDO goes to 3-state after the 17th SCK falling edge or when SDI goes high, whichever occurs first.

Care must be taken so that CNV and SDO of the devices are not low together during the read cycle.

#### Daisy-Chain Mode

Daisy-chain mode is selected if SDI is low at CNV rising edge or if SDI and CNV are connected.

#### Daisy-Chain Mode without Busy Indicator

This mode is useful in applications where the digital host has limited interfacing capability with multiple ADCs. In this mode, the CNV pins of all ADCs in the chain are connected and are controlled by a single pin of the digital host. The SCK pins are also connected and controlled by a single pin of the digital host.



Figure 10. Connection Diagram: Daisy-Chain Mode without Busy Indicator







The SDO pin is driven low when SDI and CNV are both low.

A CNV rising edge with SDI low selects daisy-chain mode, samples the analog input, and causes the device to enter a conversion phase.

In this mode, CNV must remain high from the start of the conversion until all data bits are read. When started, the conversion continues with an internal clock, regardless of the state of SCK.

However, SCK must be low at the CNV rising edge so that the device does not generate a busy indicator at the end of the conversion.

At the end of the conversion, every ADC in the chain outputs the MSB bit of the conversion result on its own SDO pin. The internal shift register of each ADC latches the data available on its SDI pin and shifts out the next bit of data on its SDO pin on every subsequent SCK falling edge.

Therefore, the digital host receives the data of ADC N at first (MSB first), followed by the data of ADC N–1, and so on. A total of  $16 \times N$  SCK falling edges are required to capture the outputs of all N devices in the chain. The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.

#### Daisy-Chain Mode with a Busy Indicator

This mode is useful in applications where the digital host has limited interfacing capability with multiple ADCs, and an interrupt-driven data transfer is desired.

In this mode, the CNV pins of all ADCs in the chain are connected and are controlled by a single pin of the digital host. The SCK pins are also connected and controlled by a single pin of the digital host.











The SDO pin is driven low when SDI and CNV are both low.

A CNV rising edge with SDI low selects daisy-chain mode, samples the analog input, and causes the device to enter a conversion phase.

In this mode, CNV must remain high from the start of the conversion until all data bits are read. When started, the conversion continues with an internal clock, regardless of the state of SCK.

However, SCK must be high at the CNV rising edge so that the device generates a busy indicator at the end of the conversion.

At the end of conversion, every ADC in the chain forces its SDO pin high, providing a low-to-high transition on the  $\overline{IRQ}$  pin of the digital host. The internal shift register of each ADC latches the data available on its SDI pin and shifts out the next bit of data on its SDO pin on every subsequent SCK falling edge. Therefore, the digital host receives the interrupt signal followed by the data of ADC N (MSB first), and then the data of ADC N–1, and so on. A total of (16 × N) + 1 SCK falling edges are required to capture the outputs of all N devices in the chain. The busy indicator bits of ADC 1 to ADC N–1 do not propagate to the next device in the chain.

The data is valid on both SCK edges. The rising edge can be used to capture the data, and SCK falling edge allows a faster reading rate if there is an acceptable hold time.



#### Application and Implementation

#### NOTE

Information in the following applications sections is not part of the 3PEAK's component specification and 3PEAK does not warrant its accuracy or completeness. 3PEAK's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### **Application Information**

The input driver and the reference driver circuits are two important circuits to maximize the performance of a high-precision, SAR ADC. Some general principles should be followed for designing these circuits.

#### **Typical Application**

#### Layout

#### Layout Guideline

Both input capacitors and output capacitors must be placed to the device pins as close as possible.

It is recommended to bypass the input pin to ground with a 0.1 µF bypass capacitor.

It is recommended to use wide trace lengths or thick copper weight to minimize I×R drop and heat dissipation.

The exposed pad must be connected to the PCB ground plane directly, the copper area must be as large as possible.

#### Layout Example



## **Tape and Reel Information**



Order Number	Package	D1 (mm)	W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P0 (mm)	W0 (mm)	Pin1 Quadrant
TPC5160-VS2R	MSOP10	330	17.6	5.2	3.3	1.5	8	12	Q1



## Package Outline Dimensions

MSOP10







Symbol		ensions llimeters	Dimensions In Inches		
	MIN	MAX	MIN	MAX	
А	0.800	1.100	0.031	0.043	
A1	0.050	0.150	0.002	0.006	
A2	0.750	0.950	0.030	0.037	
b	0.180	0.280	0.007	0.011	
с	0.090	0.230	0.004	0.009	
D	2.900	3.100	0.114	0.122	
E	4.700	5.100	0.185	0.201	
E1	2.900	3.100	0.114	0.122	
е	0.500 BSC		0.020 BSC		
L	0.400	0.800	0.016	0.031	
θ	0	8°	0	8°	

#### NOTES

- 1. Do not include mold flash or protrusion.
- 2. This drawing is subject to change without notice.





#### **Order Information**

Order Number	Operating Temperature Range	Package	Marking Information	MSL	Transport Media, Quantity	Eco Plan
TPC5160-VS2R	−40 to 125°C	MSOP10	5160	MSL1	Tape and Reel, 3000	Green

Green: 3PEAK defines "Green" to mean RoHS compatible and free of halogen substances.

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